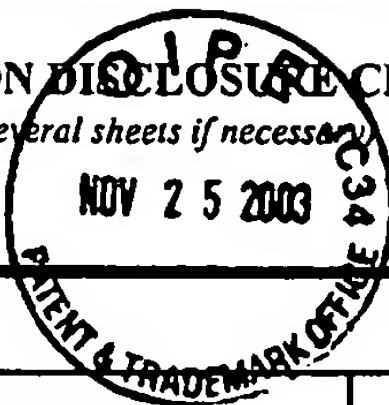


INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)



Docket Number (Optional)

WFS.011C

Application Number

10/650,666

Applicant(s)

WaveFront Sciences, Inc.

Filing Date

29 August 2003

Group Art Unit

TBD

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
gls	A	5,289,254	02/22/1994	Braunecker et al.			
	B	5,629,765	05/13/1997	Schmutz			
	C	5,841,125	11/24/1998	Livingston			
	D	5,978,053	11/02/1999	Giles et al.			
	E	6,575,572 B2	06/10/2003	Lai et al.			
gls	F	6,550,917 B1	04/22/2003	Neal et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

John Sanders

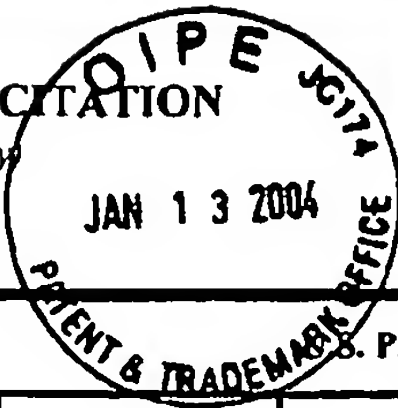
DATE CONSIDERED

6/22/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Docket Number (Optional)

WFS.011C

Application Number

10/650,666

Applicant(s)

WaveFront Sciences, Inc.

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29 August 2003

Group Art Unit

2872

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JS	A	5,825,476	10/20/98	Abitol et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

JS	B	Roggemann, Michael C. and Schulz, Timothy J., "Algorithm to increase the largest aberration that can be reconstructed from Hartmann sensor measurements," Vol. 37, No. 20, Applied Optics, 10 July 1998, pgs. 4321-4329.
JS	C	Southwell, W.H., "Wave-front estimation from wave-front slope measurements," J. Opt. Soc. Am., Vol. 70, No. 8, August 1980, pgs. 998-1006.

EXAMINER

John Sanders

DATE CONSIDERED

6/22/04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

